


SHEET 1 of 1

Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	<div> <div> 28 1996 </div> <div> PAT. &amp; TRADEMARK OFF. </div> </div>	<div> <div> 27754/32937 </div> <div> Serial No. 08/536,345 </div> </div>
<b>INFORMATION DISCLOSURE STATEMENT</b>		Applicant Stephen Temple et al.	
(Use several sheets if necessary)		Filing Date 09/29/95	Group 2108

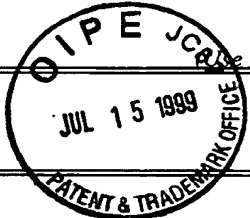
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U.S. Department of Commerce  
Patent and Trademark OfficeAtty. Docket No.  
27754/32937Serial No.  
08/536,345

## INFORMATION DISCLOSURE STATEMENT

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2851

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## U.S. PATENT DOCUMENTS

*Examiner Initials	Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
<i>[Signature]</i>	3,245,895	04/12/66	Baker et al.	204	164	2-21-55
<i>[Signature]</i>	4,828,870	05/09/89	Ando et al.	427	38	—
<i>[Signature]</i>	4,997,673	03/05/91	Ogata et al.	427	38	—
<i>[Signature]</i>	5,053,245	10/01/91	Kiyama et al.	427	38	10/25/90
<i>[Signature]</i>	5,235,352	08/10/93	Pies et al.	346	140R	08/16/91
<i>[Signature]</i>	5,406,319	04/11/95	Hayes et al.	347	71	05/20/93
<i>[Signature]</i>	5,619,235	04/08/97	Suzuki et al.	347	69	09/28/94

## FOREIGN PATENT DOCUMENTS

*Examiner Initials	Document Number	Publication Date	Country	Class	Subclass	Translation No
<i>[Signature]</i>	0 364 136 A2	04/18/90	EPO	—	—	—
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TECHNOLOGY CENTER 2800						—

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

<i>[Signature]</i>	Laser Deposition of AlN Thin Films on InP and GaAs, Bhattacharya et al., Japanese Journal of Applied Physics Vol. 30, No. 10A, October, 1991, pp. L1750-L1752

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